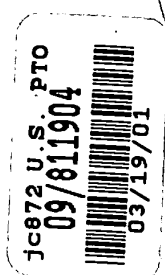


**FORM PTO-1449**  
**U.S. DEPARTMENT OF COMMERCE**  
**PATENT AND TRADEMARK OFFICE**



ATTY DOCKET NO. 11460-109  
Sheet 1 of 1

Applicants: Richard P. Torti, et al.  
Serial Number: N/A  
Filed: Herewith

Examiner: N/A  
Group Art Unit: N/A

For: CLUSTER SIZE MEASUREMENT INSTRUMENT AND METHOD FOR CLUSTER  
ION BEAM DIAGNOSTIC

**U.S. PATENT DOCUMENTS**

EXAMINER INI- ITEM DOCUMENT				SUB		FILING DATE IF
TIAL NO.	NUMBER	DATE	NAME	CLASS	CLASS	APPROP.
ve 1.	5,814,194	09/29/98	Deguchi et al.	204	192.1	
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ve 3.	4,737,637	04/12/98	Knauer	250	281	
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**FOREIGN PATENT DOCUMENTS**

EXAMINER INI- ITEM DOCUMENT				SUB		TRANSLATION	
TIAL NO.	NUMBER	DATE	NAME	CLASS	CLASS	YES	NO
ve	03245523 JP	11/01/91	Aoyanagi Toshitaka				+
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2. N. Kofuji, et al., "Development of gas cluster source and its characteristics", Proc. 14<sup>th</sup> Symp. On Ion Sources and Ion-Assisted Technology, Tokyo (1991) p.15
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4. N. Toyoda, "Nano-Processing with Gas Cluster Ion Beams", sections 3.1 and 3.2, doctoral thesis, Kyoto Univ., Kyoto, JP, 1999

<b>EXAMINER</b>	<b>DATE CONSIDERED</b>
ZIA R-HASHMI	7/9/03



**FORM PTO-1449**  
**U.S. DEPARTMENT OF COMMERCE**  
**PATENT AND TRADEMARK OFFICE**

ATTORNEY DOCKET NO.: 11460-109

APPLICATION SERIAL NO.: 09/811,904

GROUP ART UNIT: 2881

APPLICANT: Richard P. Torti, et al.

EXAMINER: N/A

FILING DATE: March 19, 2001

CONFIRMATION NO.: 7642

**U.S. PATENT DOCKETS**

EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS/SUB- CLASS	FILING DATE IF APPROPRIATE
WE	5,382,793	01/17/95	Weinberger, et al.	250/288	03/06/92
WE	5,659,170	08/19/97	Da Silva, et al.	250/287	12/16/94

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS/SUB- CLASS	TRANSLATION YES NO

**OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, etc.)

\* If any such item is considered sufficiently relevant by the Examiner to the present invention, its possible "prior art" status against the present invention should be considered individually allowing for the prospect of Applicants' swearing back or other priority determination.

**EXAMINER****DATE CONSIDERED**

ZIA R. HASANI

7/9/03